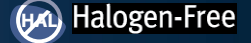
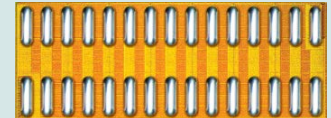


## EPC2023 – Enhancement Mode Power Transistor

 $V_{DS}$ , 30 V $R_{DS(on)}$ , 1.45 mΩ $I_D$ , 90 A

Gallium Nitride's exceptionally high electron mobility and low temperature coefficient allows very low  $R_{DS(on)}$ , while its lateral device structure and majority carrier diode provide exceptionally low  $Q_G$  and zero  $Q_{RR}$ . The end result is a device that can handle tasks where very high switching frequency, and low on-time are beneficial as well as those where on-state losses dominate.



EPC2023 eGaN® FETs are supplied only in passivated die form with solder bumps. Die Size: 6.05 mm x 2.3 mm

Applications:

- High Frequency DC-DC Conversion
- Point-of-Load (POL) Converters
- Motor Drive
- Industrial Automation

| Maximum Ratings |                                                                               |            |                  |
|-----------------|-------------------------------------------------------------------------------|------------|------------------|
| PARAMETER       |                                                                               | VALUE      | UNIT             |
| $V_{DS}$        | Drain-to-Source Voltage (Continuous)                                          | 30         | V                |
|                 | Drain-to-Source Voltage (up to 10,000 5 ms pulses at 150°C)                   | 36         |                  |
| $I_D$           | Continuous ( $T_A = 25^\circ\text{C}$ , $R_{\theta JA} = 6^\circ\text{C/W}$ ) | 90         | A                |
|                 | Pulsed ( $25^\circ\text{C}$ , $T_{PULSE} = 300 \mu\text{s}$ )                 | 590        |                  |
| $V_{GS}$        | Gate-to-Source Voltage                                                        | 6          | V                |
|                 | Gate-to-Source Voltage                                                        | -4         |                  |
| $T_J$           | Operating Temperature                                                         | -40 to 150 | $^\circ\text{C}$ |
| $T_{STG}$       | Storage Temperature                                                           | -40 to 150 |                  |

| Thermal Characteristics |                                                  |     |                    |
|-------------------------|--------------------------------------------------|-----|--------------------|
| PARAMETER               |                                                  | TYP | UNIT               |
| $R_{\theta JC}$         | Thermal Resistance, Junction-to-Case             | 0.4 | $^\circ\text{C/W}$ |
| $R_{\theta JB}$         | Thermal Resistance, Junction-to-Board            | 1.1 |                    |
| $R_{\theta JA}$         | Thermal Resistance, Junction-to-Ambient (Note 1) | 42  |                    |

Note 1:  $R_{\theta JA}$  is determined with the device mounted on one square inch of copper pad, single layer 2 oz copper on FR4 board. See [https://epc-co.com/epc/documents/product-training/Appnote\\_Thermal\\_Performance\\_of\\_eGaN\\_FETs.pdf](https://epc-co.com/epc/documents/product-training/Appnote_Thermal_Performance_of_eGaN_FETs.pdf) for details.

| Static Characteristics ( $T_J = 25^\circ\text{C}$ unless otherwise stated) |                                |                                                  |     |      |      |      |
|----------------------------------------------------------------------------|--------------------------------|--------------------------------------------------|-----|------|------|------|
| PARAMETER                                                                  |                                | TEST CONDITIONS                                  | MIN | TYP  | MAX  | UNIT |
| $BV_{DSS}$                                                                 | Drain-to-Source Voltage        | $V_{GS} = 0 \text{ V}$ , $I_D = 1.3 \text{ mA}$  | 30  |      |      | V    |
| $I_{DSS}$                                                                  | Drain-Source Leakage           | $V_{GS} = 0 \text{ V}$ , $V_{DS} = 24 \text{ V}$ |     | 0.1  | 1    | mA   |
| $I_{GSS}$                                                                  | Gate-to-Source Forward Leakage | $V_{GS} = 5 \text{ V}$                           |     | 1    | 9    | mA   |
|                                                                            | Gate-to-Source Reverse Leakage | $V_{GS} = -4 \text{ V}$                          |     | 0.1  | 1    | mA   |
| $V_{GS(TH)}$                                                               | Gate Threshold Voltage         | $V_{DS} = V_{GS}$ , $I_D = 20 \text{ mA}$        | 0.8 | 1.4  | 2.5  | V    |
| $R_{DS(on)}$                                                               | Drain-Source On Resistance     | $V_{GS} = 5 \text{ V}$ , $I_D = 40 \text{ A}$    |     | 1.15 | 1.45 | mΩ   |
| $V_{SD}$                                                                   | Source-Drain Forward Voltage   | $I_S = 0.5 \text{ A}$ , $V_{GS} = 0 \text{ V}$   |     | 1.5  |      | V    |

All measurements were done with substrate connected to source.

Dynamic Characteristics ( $T_J = 25^\circ\text{C}$  unless otherwise stated)

| PARAMETER     |                                                       | TEST CONDITIONS                                                | MIN | TYP  | MAX  | UNIT     |
|---------------|-------------------------------------------------------|----------------------------------------------------------------|-----|------|------|----------|
| $C_{ISS}$     | Input Capacitance                                     | $V_{DS} = 15\text{ V}, V_{GS} = 0\text{ V}$                    |     | 2150 | 2600 | pF       |
| $C_{OSS}$     | Output Capacitance                                    |                                                                |     | 1530 | 2300 |          |
| $C_{RSS}$     | Reverse Transfer Capacitance                          |                                                                |     | 100  |      |          |
| $C_{OSS(ER)}$ | Effective Output Capacitance, Energy Related (Note 2) | $V_{DS} = 0\text{ to }15\text{ V}, V_{GS} = 0\text{ V}$        |     | 1850 |      |          |
| $C_{OSS(TR)}$ | Effective Output Capacitance, Time Related (Note 3)   |                                                                |     | 2020 |      |          |
| $R_G$         | Gate Resistance                                       |                                                                |     | 0.3  |      | $\Omega$ |
| $Q_G$         | Total Gate Charge                                     | $V_{DS} = 15\text{ V}, V_{GS} = 5\text{ V}, I_D = 40\text{ A}$ |     | 19   | 25   | nC       |
| $Q_{GS}$      | Gate-to-Source Charge                                 | $V_{DS} = 15\text{ V}, I_D = 40\text{ A}$                      |     | 5.7  |      |          |
| $Q_{GD}$      | Gate-to-Drain Charge                                  |                                                                |     | 3.2  |      |          |
| $Q_{G(TH)}$   | Gate Charge at Threshold                              |                                                                |     | 4    |      |          |
| $Q_{OSS}$     | Output Charge                                         | $V_{DS} = 15\text{ V}, V_{GS} = 0\text{ V}$                    |     | 30   | 45   |          |
| $Q_{RR}$      | Source-Drain Recovery Charge                          |                                                                |     | 0    |      |          |

All measurements were done with substrate connected to source.

Note 2:  $C_{OSS(ER)}$  is a fixed capacitance that gives the same stored energy as  $C_{OSS}$  while  $V_{DS}$  is rising from 0 to 50%  $BV_{DSS}$ .

Note 3:  $C_{OSS(TR)}$  is a fixed capacitance that gives the same charging time as  $C_{OSS}$  while  $V_{DS}$  is rising from 0 to 50%  $BV_{DSS}$ .

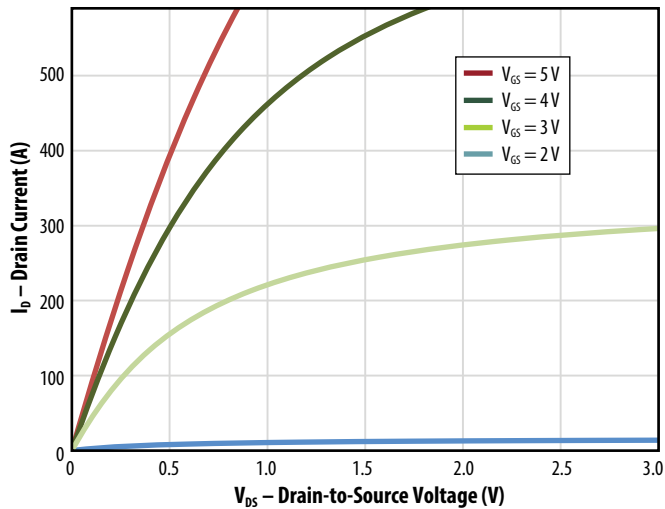
Figure 1: Typical Output Characteristics at  $25^\circ\text{C}$ 

Figure 2: Transfer Characteristics

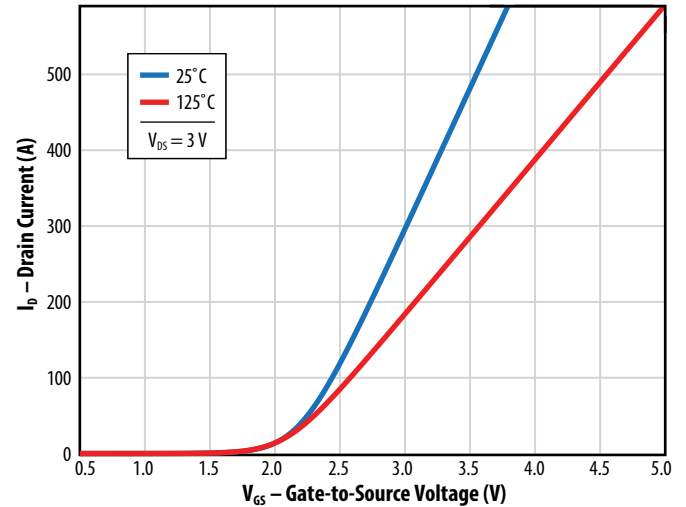
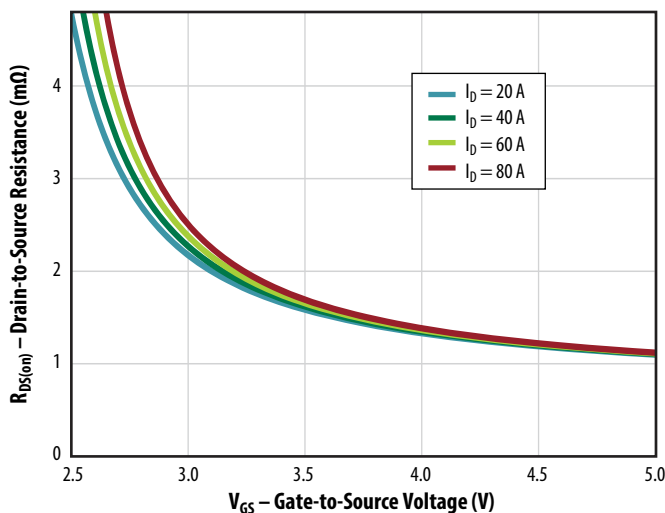
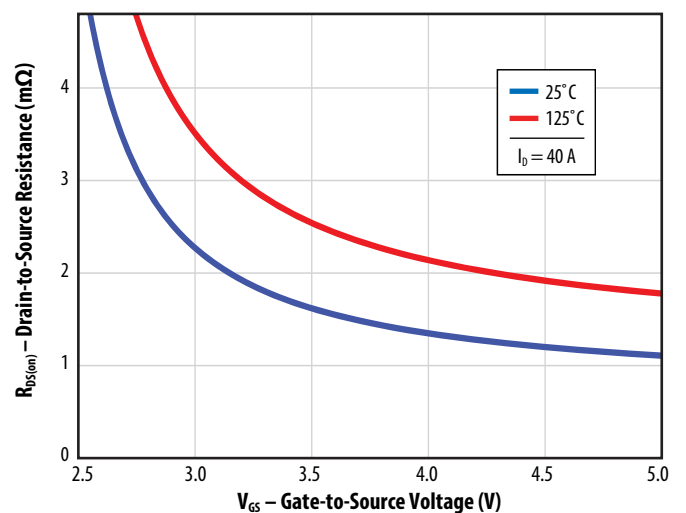
Figure 3:  $R_{DS(on)}$  vs.  $V_{GS}$  for Various Drain CurrentsFigure 4:  $R_{DS(on)}$  vs.  $V_{GS}$  for Various Temperatures

Figure 5a: Capacitance (Linear Scale)

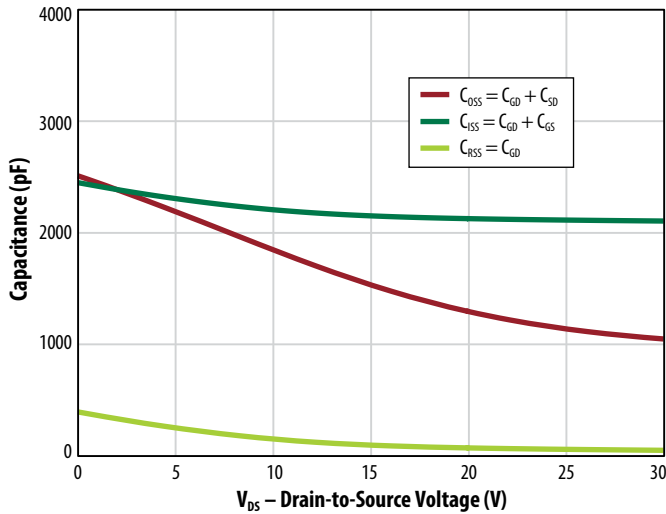


Figure 5b: Capacitance (Log Scale)

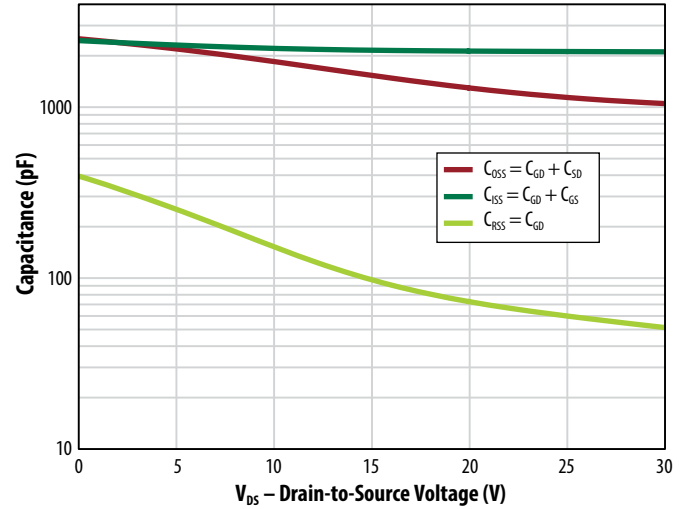
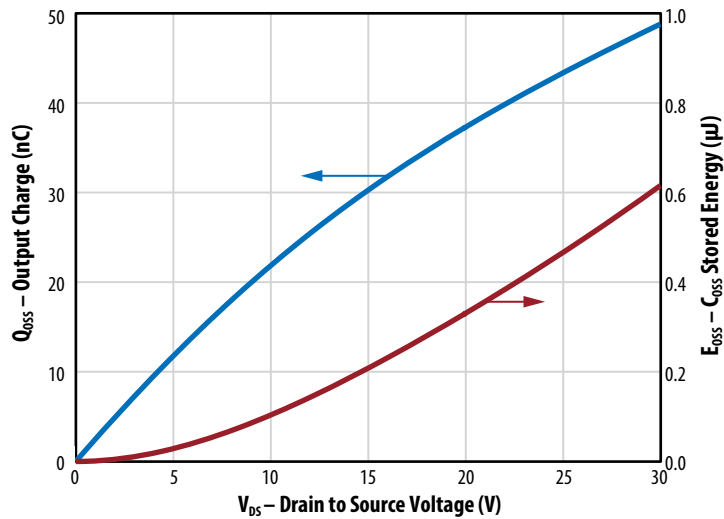
Figure 6: Output Charge and  $C_{OSS}$  Stored Energy

Figure 7: Gate Charge

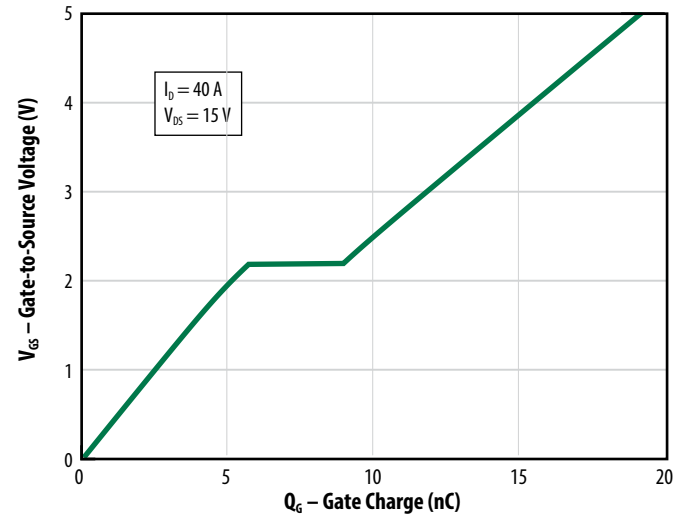


Figure 8: Reverse Drain-Source Characteristics

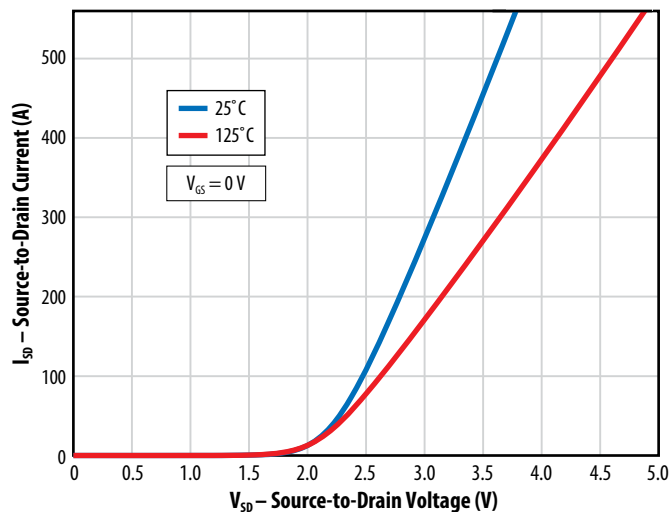
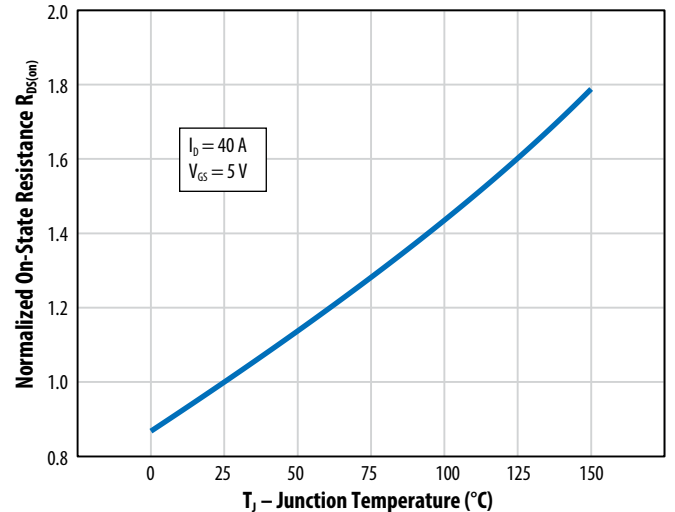


Figure 9: Normalized On-State Resistance vs. Temperature



All measurements were done with substrate shorted to source.

Figure 10: Normalized Threshold Voltage vs. Temperature

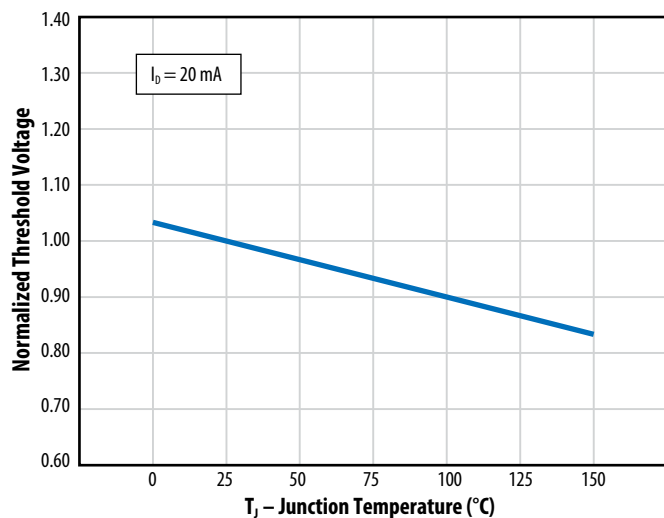


Figure 11: Safe Operating Area

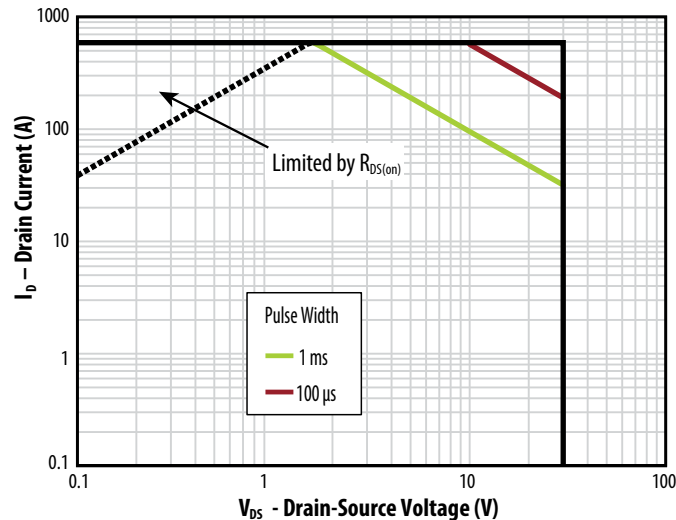
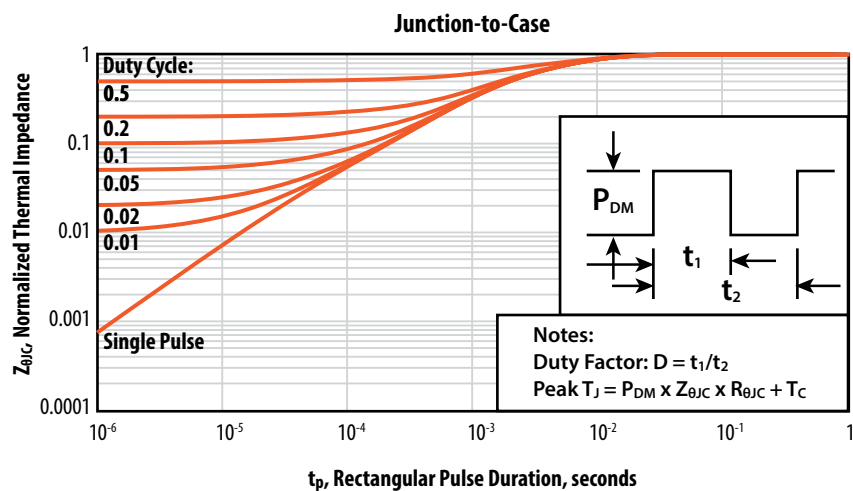
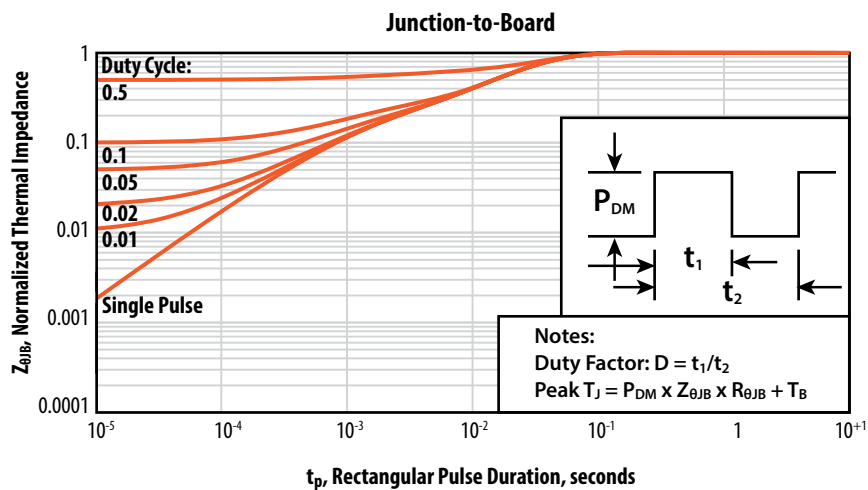
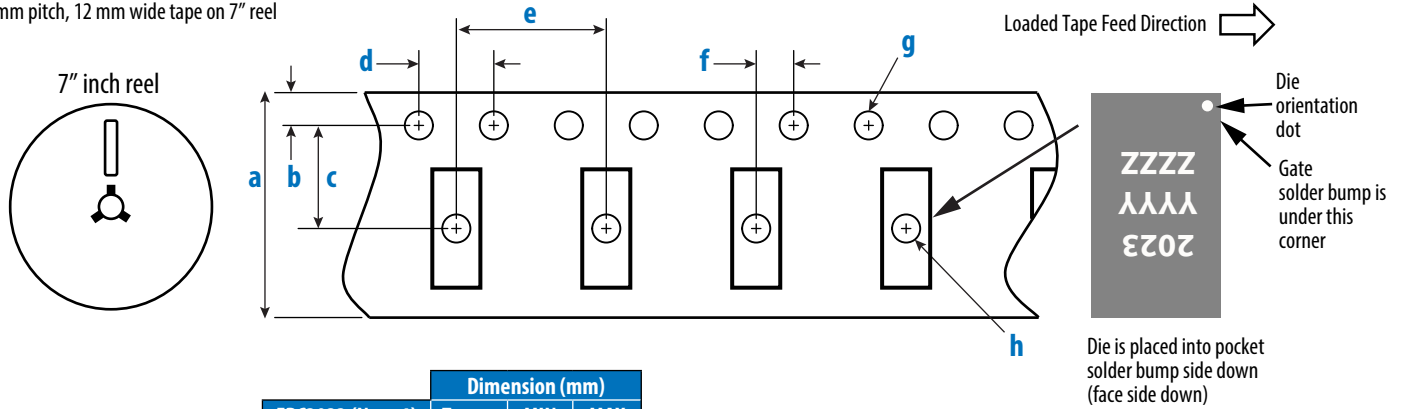


Figure 12: Transient Thermal Response Curves



## TAPE AND REEL CONFIGURATION

8 mm pitch, 12 mm wide tape on 7" reel

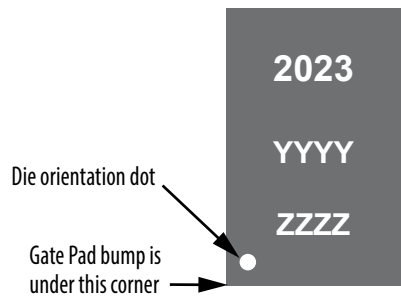


| EPC2023 (Note 1) | Dimension (mm) |       |       |
|------------------|----------------|-------|-------|
|                  | Target         | MIN   | MAX   |
| a                | 12.00          | 11.90 | 12.30 |
| b                | 1.75           | 1.65  | 1.85  |
| c (Note 2)       | 5.50           | 5.45  | 5.55  |
| d                | 4.00           | 3.90  | 4.10  |
| e                | 8.00           | 7.90  | 8.10  |
| f (Note 2)       | 2.00           | 1.95  | 2.05  |
| g                | 1.50           | 1.50  | 1.60  |
| h                | 1.50           | 1.50  | 1.75  |

Note 1: MSL 1 (moisture sensitivity level 1) classified according to IPC/JEDEC industry standard.

Note 2: Pocket position is relative to the sprocket hole measured as true position of the pocket, not the pocket hole.

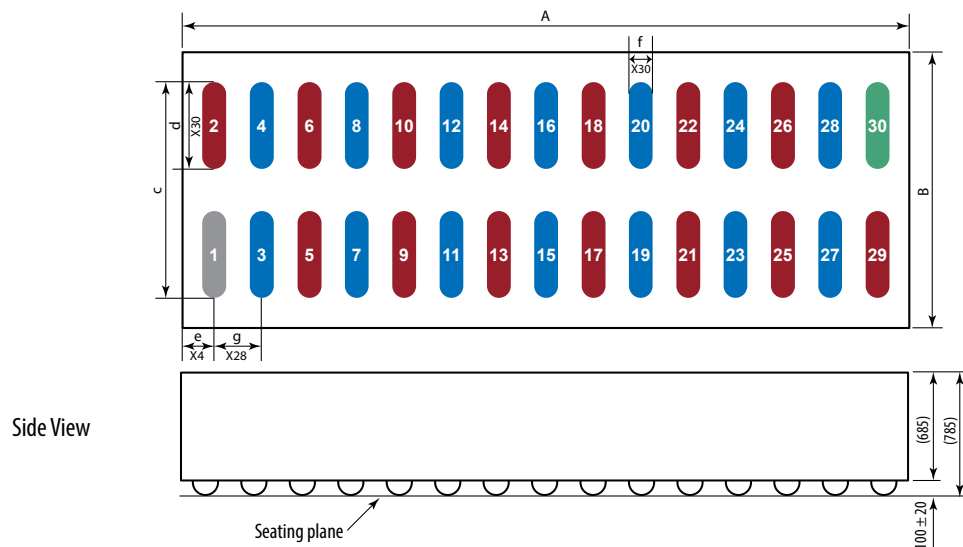
## DIE MARKINGS



| Part Number | Laser Markings        |                              |                              |
|-------------|-----------------------|------------------------------|------------------------------|
|             | Part # Marking Line 1 | Lot Date Code Marking Line 2 | Lot Date Code Marking Line 3 |
| EPC2023     | 2023                  | YYYY                         | ZZZZ                         |

## DIE OUTLINE

Solder Bump View



| DIM | Micrometers |         |      |
|-----|-------------|---------|------|
|     | MIN         | Nominal | MAX  |
| A   | 6020        | 6050    | 6080 |
| B   | 2270        | 2300    | 2330 |
| C   | 2047        | 2050    | 2053 |
| D   | 717         | 720     | 723  |
| E   | 210         | 225     | 240  |
| F   | 195         | 200     | 205  |
| G   | 400         | 400     | 400  |

Pad 1 is Gate;

Pads 2, 5, 6, 9, 10, 13, 14, 17, 18, 21, 22, 25, 26, 29 are Source;

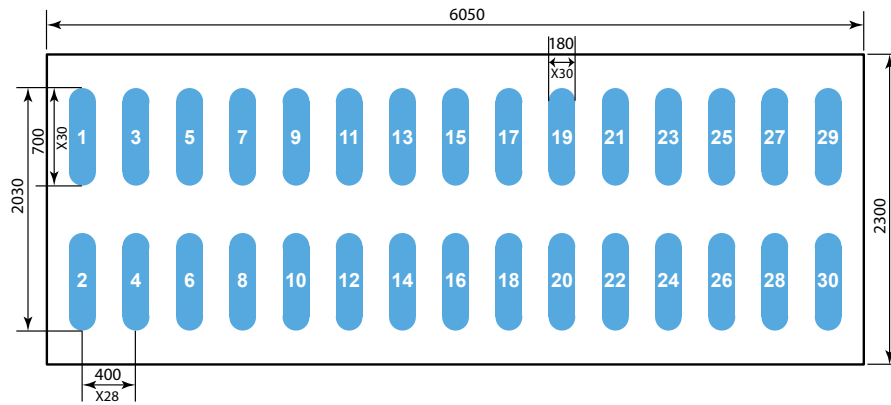
Pads 3, 4, 7, 8, 11, 12, 15, 16, 19, 20, 23, 24, 27, 28 are Drain;

Pad 30 is Substrate.\*

\*Substrate pin should be connected to Source

## RECOMMENDED LAND PATTERN

(units in  $\mu\text{m}$ )



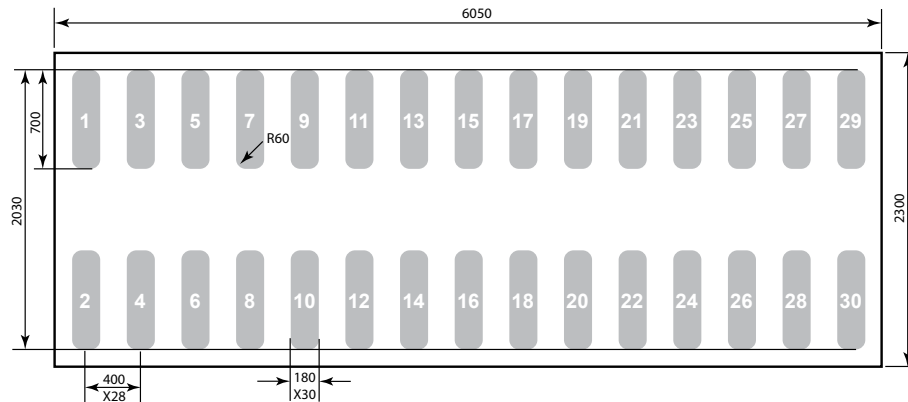
Land pattern is solder mask defined  
Solder mask opening is 180  $\mu\text{m}$   
It is recommended to have on-Cu trace PCB vias

Pad 1 is Gate;  
Pads 2, 5, 6, 9, 10, 13, 14, 17, 18, 21, 22, 25, 26, 29 are Source;  
Pads 3, 4, 7, 8, 11, 12, 15, 16, 19, 20, 23, 24, 27, 28 are Drain;  
Pad 30 is Substrate.\*

\*Substrate pin should be connected to Source

## RECOMMENDED STENCIL DRAWING

(units in  $\mu\text{m}$ )



Recommended stencil should be 4 mil (100  $\mu\text{m}$ ) thick, must be laser cut, openings per drawing.

Intended for use with SAC305 Type 4 solder, reference 88.5% metals content.

Additional assembly resources available at  
<https://epc-co.com/epc/DesignSupport/AssemblyBasics.aspx>

Efficient Power Conversion Corporation (EPC) reserves the right to make changes without further notice to any products herein to improve reliability, function or design. EPC does not assume any liability arising out of the application or use of any product or circuit described herein; neither does it convey any license under its patent rights, nor the rights of others.

eGaN® is a registered trademark of Efficient Power Conversion Corporation.  
EPC Patent Listing: [epc-co.com/epc/AboutEPC/Patents.aspx](https://epc-co.com/epc/AboutEPC/Patents.aspx)

Information subject to  
change without notice.  
Revised May, 2022